

Notice of References Cited

Application/Control No.

09/480,223

Applicant(s)/Patent Under
Reexamination
WHISTON ET AL.

Examiner

Yennhu B Huynh

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,426,258 B1	07-2002	Harada et al.	438/268
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ohzone et al., "Electrical Characteristics of Scaled CMOSFET's with Source/Drain Regions Fabricated by 7 degrees and 0 degrees Tilt-Angle Implantations", IEEE, Vol. 42, No.1, pp. 70-77, Jan./1995.
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	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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